## Notice of References Cited Application/Control No. O9/916,112 Examiner J. Derek Rutten Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*	,	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,237,144 B1	05-2001	Delo, John C.	717/174
	В	US-2004/0015831 A1	01-2004	Bowhill, Allan J.C.	717/106
	С	US-5,293,479 A	03-1994	Quintero et al.	715/841
	D	US-5,963,743 A	10-1999	Amberg et al.	717/174
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р			`		
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	V	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.